

Ch Power MOS

S=

Electrical Characteristics at $T_J=25^{\circ}\text{C}$ (unless otherwise specified)
Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\text{ A}$	150	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\text{ A}$	2	3	4	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0V, V_{DS}=150V, T_J=25^{\circ}\text{C}$	-	-	1	A
		$V_{GS}=0V, V_{DS}=150V, T_J=100^{\circ}\text{C}$	-	-	100	
Gate to Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$ TO-263	-	7.9	8.8	m
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$ TO-220	-	7.9	8.8	m
Transconductance	g_{fs}	$V_{DS}=5V, I_D=20A$	-	70	-	S
Gate Resistance	R_G	$V_{GS}=0V, V_{DS}\text{ Open}, f=1\text{MHz}$	-	0.95	-	

Dynamic Characteristics

Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=75V, f=1\text{MHz}$	-	4362	-	pF
Output Capacitance	C_{oss}		-	333	-	
Reverse Transfer Capacitance	C_{riss}		-	11.5	-	
Total Gate Charge	$Q_g(10V)$	$V_{DD}=75V, I_D=20A, V_{GS}=10V$	-	52	-	nC
Gate to Source Charge	Q_{gs}		-	19	-	
Gate to Drain (Miller) Charge	Q_{gd}		-	5	-	
Turn on Delay Time	$t_{d(on)}$	$V_{DD}=75V, I_D=20A, V_{GS}=10V, R_G=10\text{ }\Omega$	-	19	-	ns
Rise time	t_r		-	10	-	
Turn off Delay Time	$t_{d(off)}$		-	29	-	
Fall Time	t_f		-	12	-	

Reverse Diode Characteristics

Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_F=20A$	-	0.9	1.2	V
Reverse Recovery Time	t_{rr}	$V_R=75V, I_F=20A, dI_F/dt=100A/\text{s}$	-	80	-	ns
Reverse Recovery Charge	Q_{rr}		-	160	-	nC

Fig 1. Typical Output Characteristics

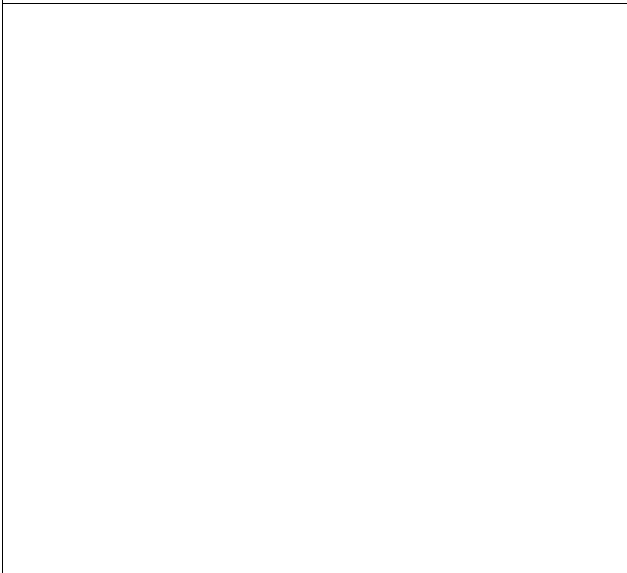


Figure 2. On-Resistance vs. Gate-Source Voltage

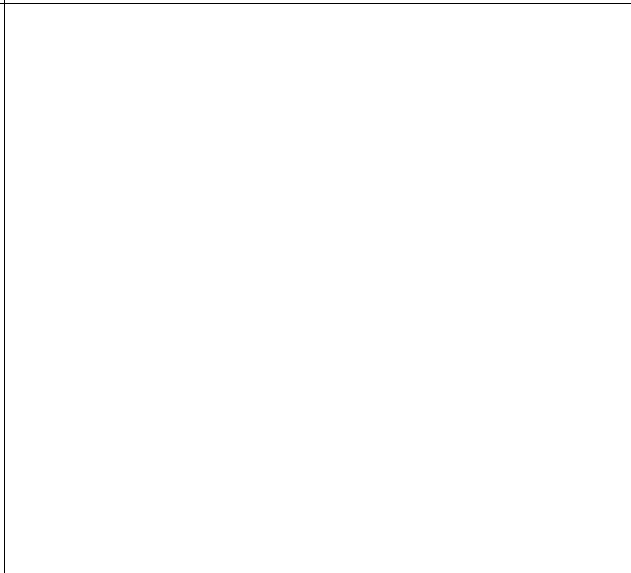


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

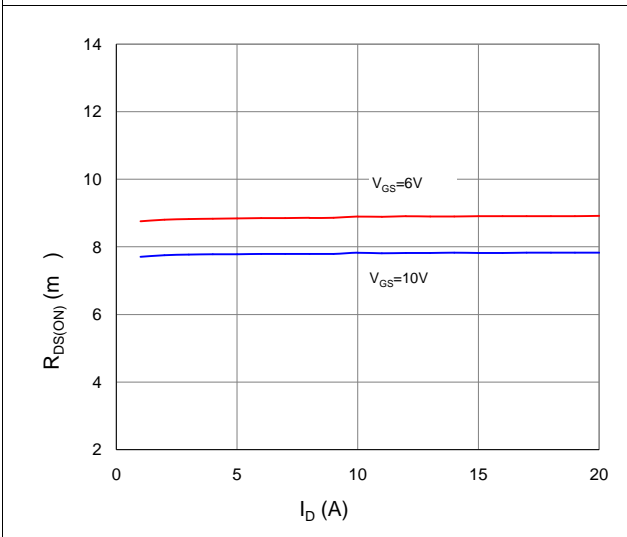


Figure 4. Normalized On-Resistance vs. Junction Temperature

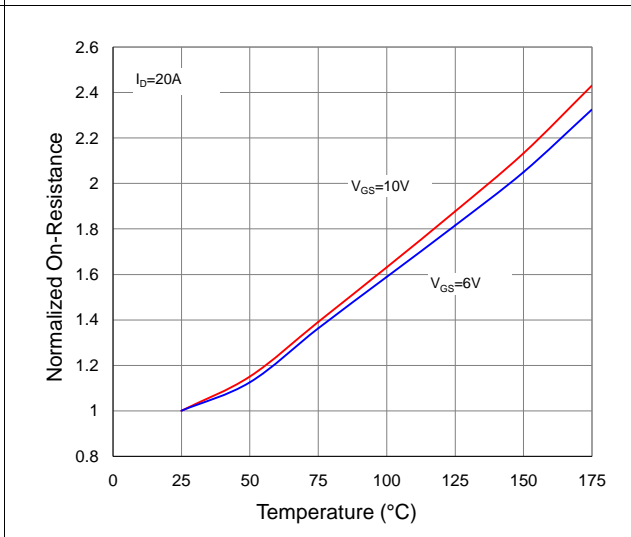


Figure 5. Typical Transfer Characteristics

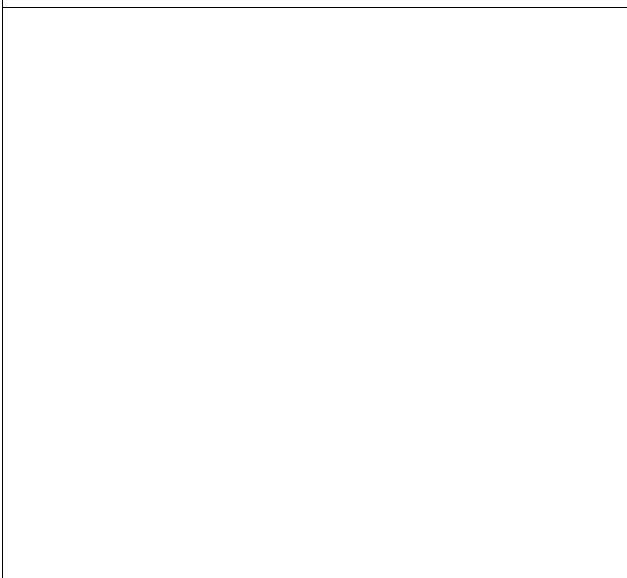


Figure 6. Typical Source-Drain Diode Forward Voltage

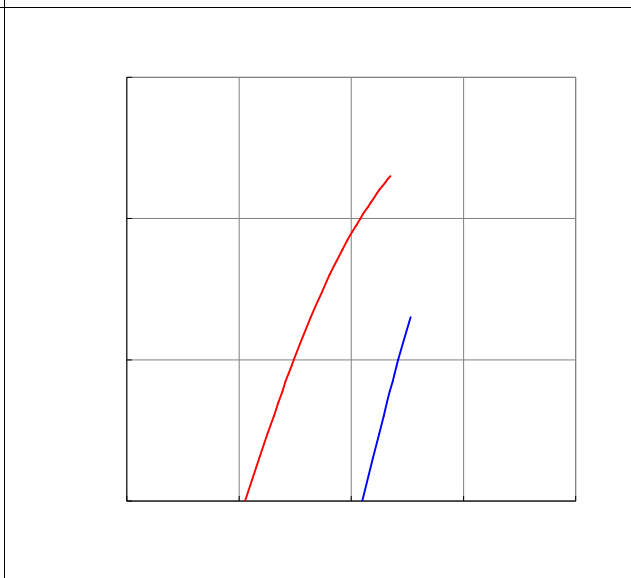


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

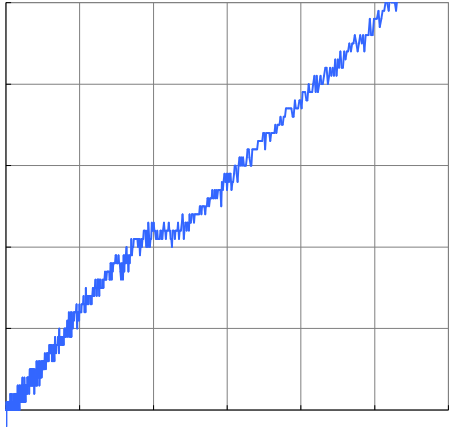


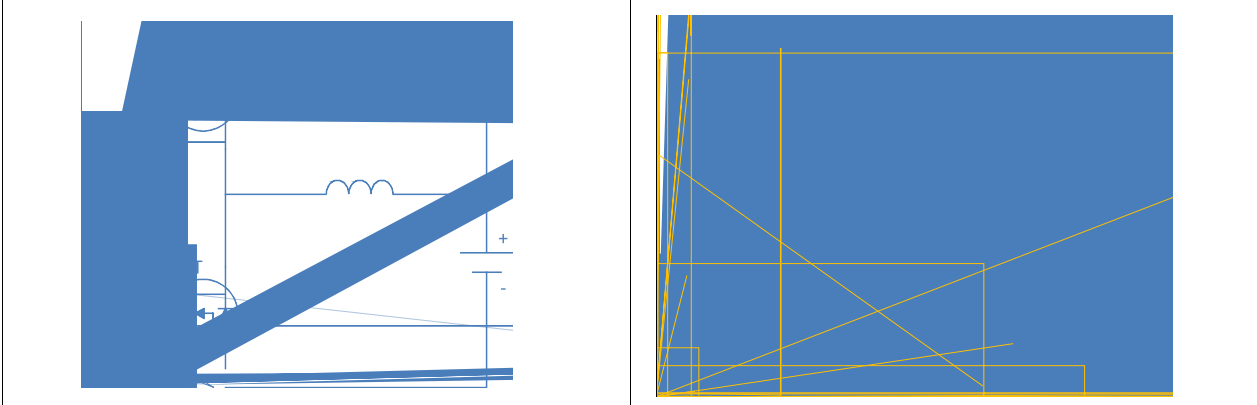
Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

Figure 9. Maximum Safe Operating Area

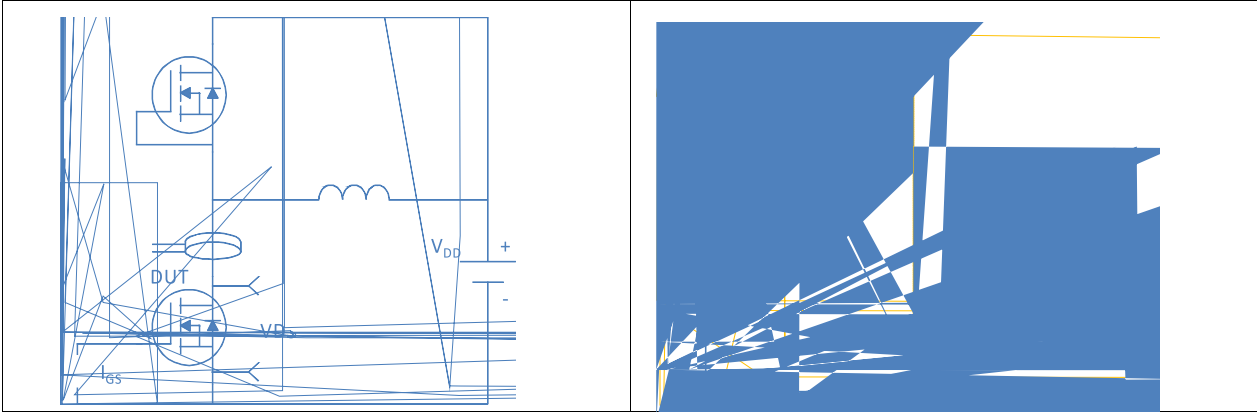
Figure 10. Maximum Drain Current vs. Case Temperature

Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Ambient

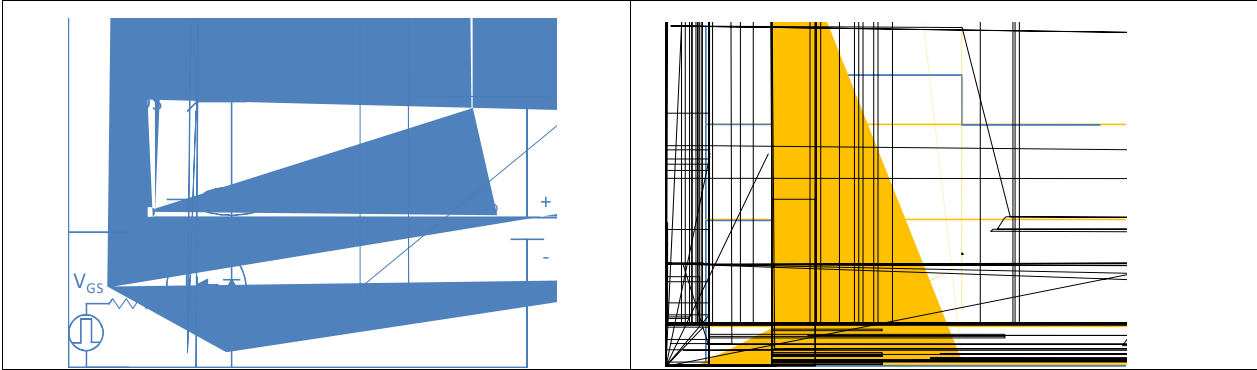
Inductive switching Test



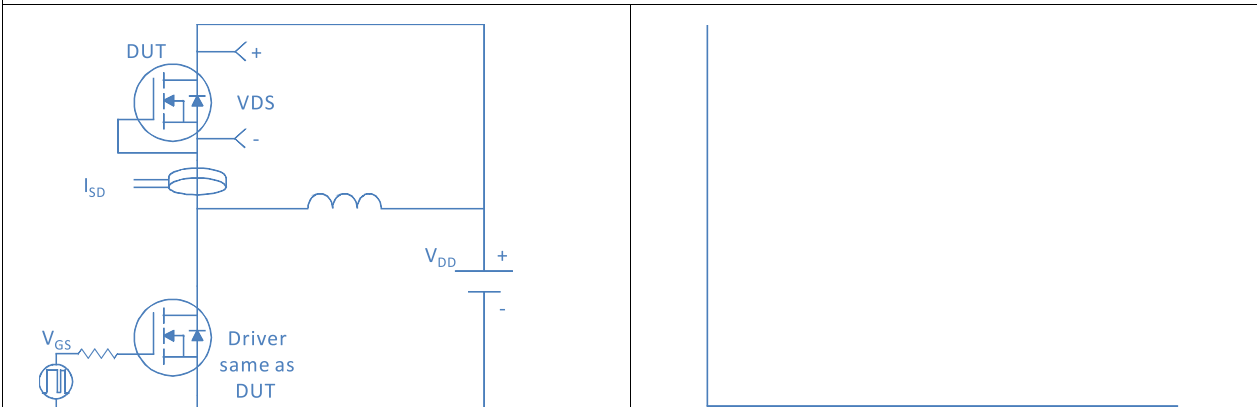
Gate Charge Test



Uclamped Inductive Switching (UIS) Test

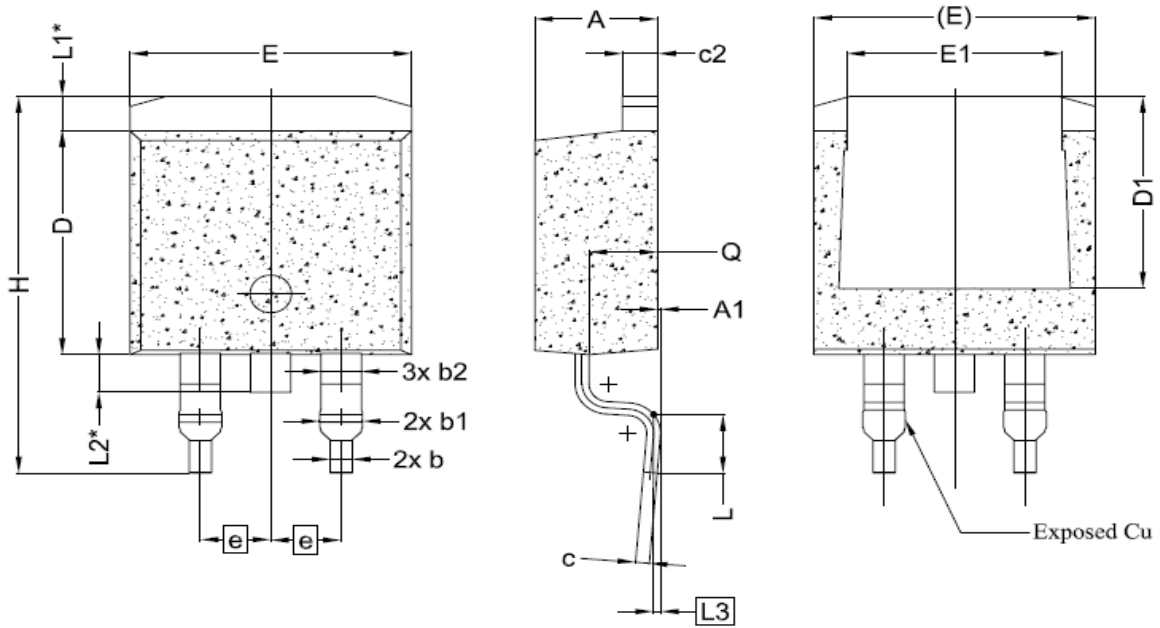


Diode Recovery Test



Package Outline

TO-263, 3 leads



Symbol	Value	Value	Symbol	Value
L1*	4.54	4.27	A	1.27
E	2.54	2.54	c2	0.25
D	2.54	2.54	Q	0.25
H	3.00	3.00	A1	0.25
L2*	1.50	1.78	c	0.25
b2	1.27	1.27	L3	0.25
b1	1.27	1.27		
b	1.27	1.27		
e	0.50	0.50		
2.54 BSC:				
H	15.00	15.88		
L	2.32	2.79		
1.35 REF.				
1.50 REF.				
0.25 BSC:				
Q	2.30	2.48		
		2.70		